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Oonuma et al.

(10) **Patent No.: US D635,167 S**
(45) **Date of Patent: ** *Mar. 29, 2011**

(54) **PORTION OF AN ELECTRON MICROSCOPE**

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(*) Notice: This patent is subject to a terminal disclaimer.

(**) Term: **14 Years**

(21) Appl. No.: **29/356,716**

(22) Filed: **Mar. 2, 2010**

(30) **Foreign Application Priority Data**

Sep. 25, 2009 (JP) 2009-022088

(51) **LOC (9) Cl.** **16-06**
(52) **U.S. Cl.** **D16/131**
(58) **Field of Classification Search** D16/130, D16/131, 221, 234; D24/186, 232, 216, D24/233; D10/81; D13/184; 250/311; 359/383, 359/384, 385, 389, 390, 368, 370, 371, 372, 359/363; D7/601, 609, 323, 328, 350.1, D7/350.2, 350.3; 312/114, 117, 138.1, 351; D6/627; 206/558
See application file for complete search history.

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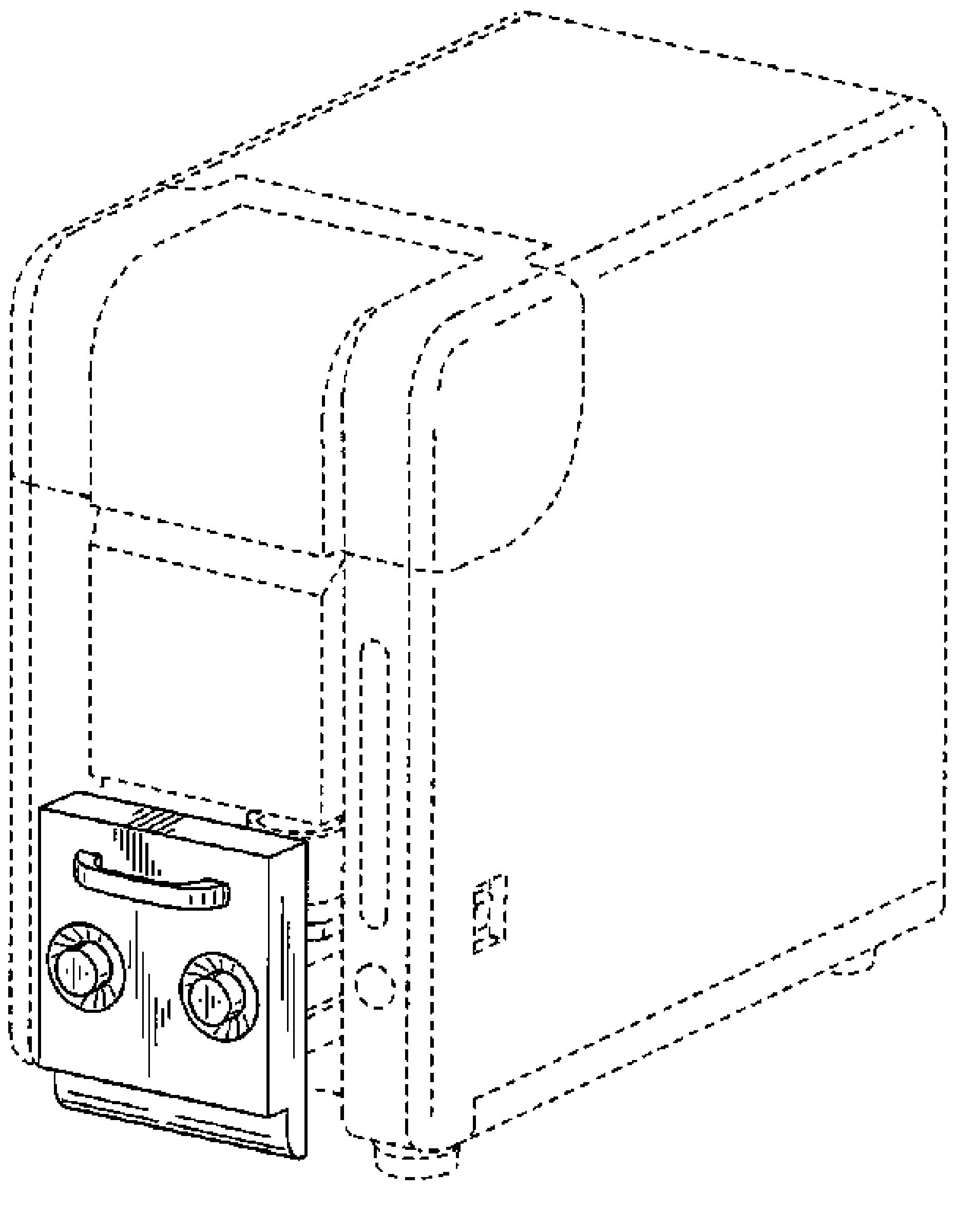
(57) **CLAIM**

We claim the ornamental design for a portion of an electron microscope, as shown and described.

DESCRIPTION

FIG. **1** is a front, top and right side perspective view of a portion of an electron microscope showing our new design;
FIG. **2** is a front elevational view thereof; the rear view is not part of the claimed design;
FIG. **3** is a rear elevational view thereof;
FIG. **4** is a left side elevational view thereof;
FIG. **5** is a right side elevational view thereof;
FIG. **6** is a top plan view thereof;
FIG. **7** is a bottom plan view thereof; and,
FIG. **8** is a front, top and right side perspective view thereof shown in an opened positioned; the front, top and left side perspective view of the claimed design (shown in solid lines) is a mirror image of the claimed design as shown in FIG. **8**. The broken lines shown are for illustrative purpose and form no part of the claimed design.

1 Claim, 8 Drawing Sheets



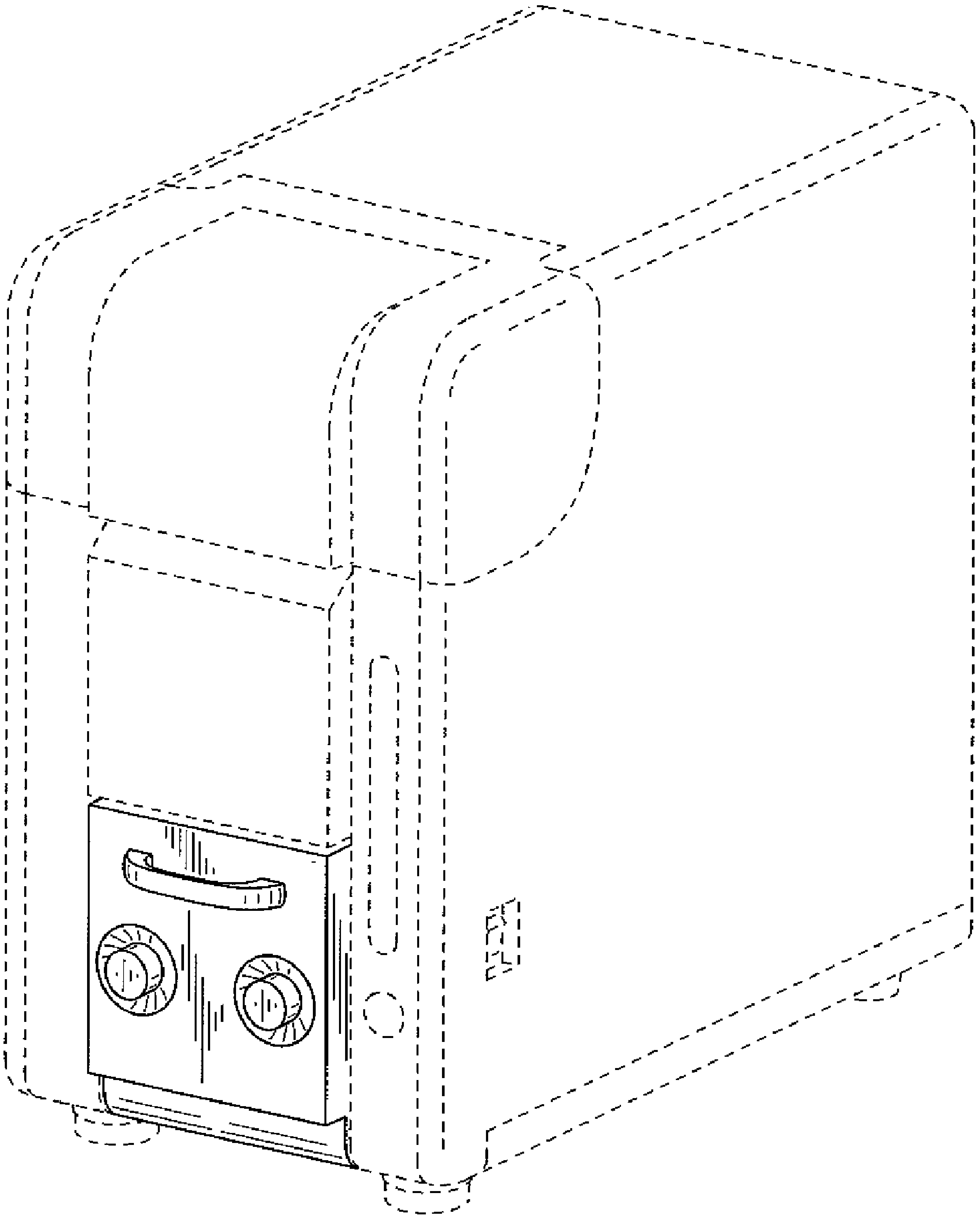


FIG. 1

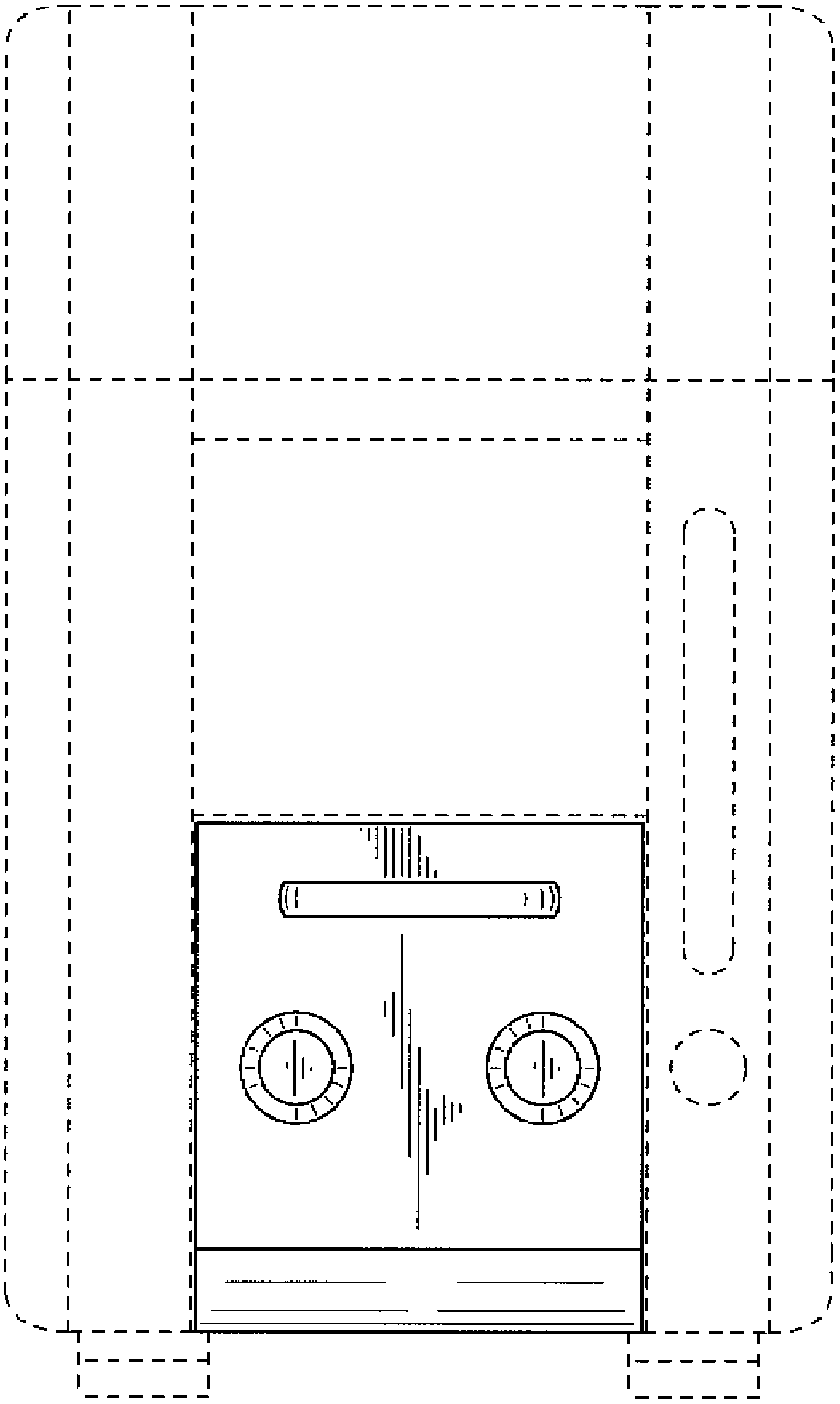


FIG. 2

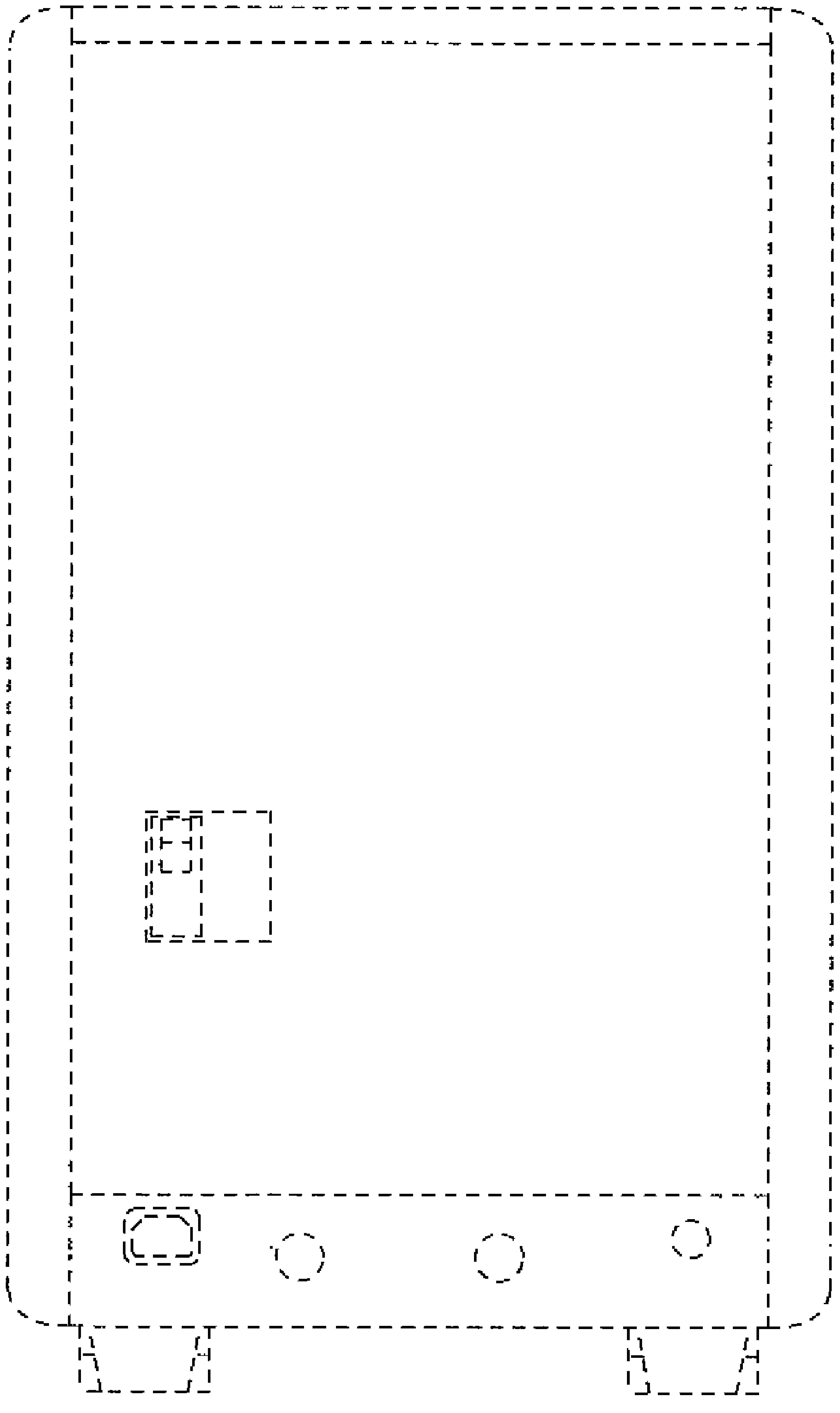


FIG. 3

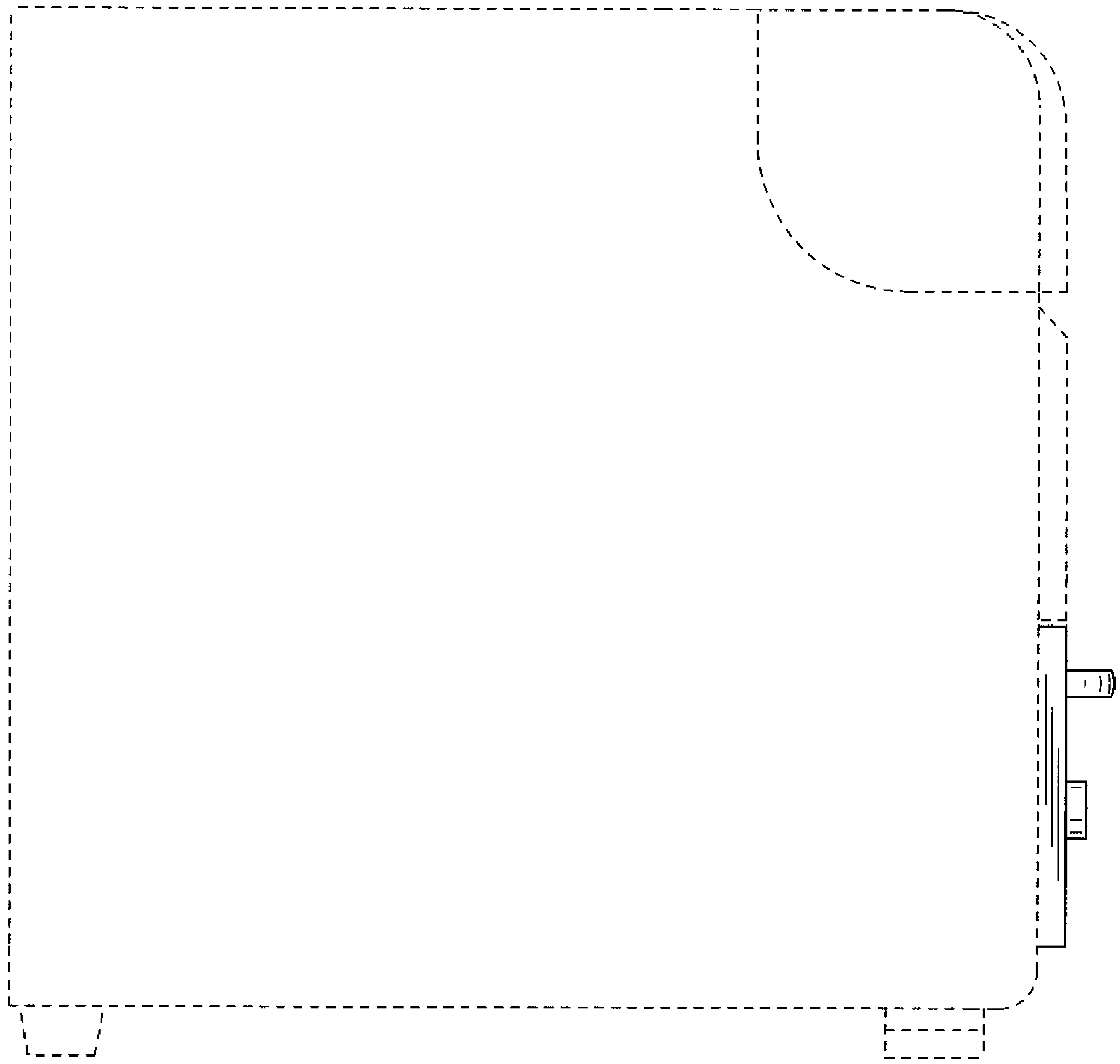


FIG. 4

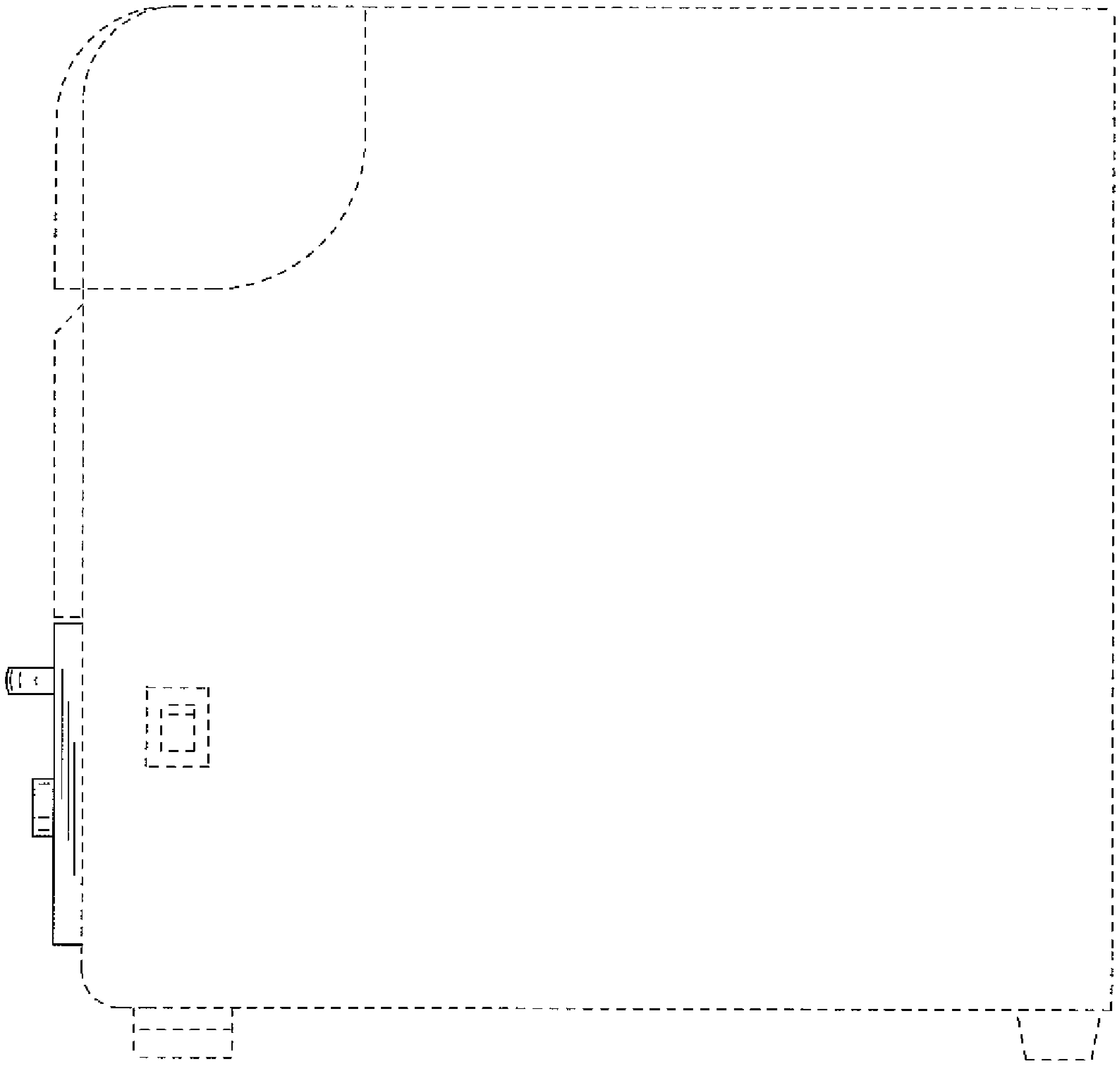


FIG. 5

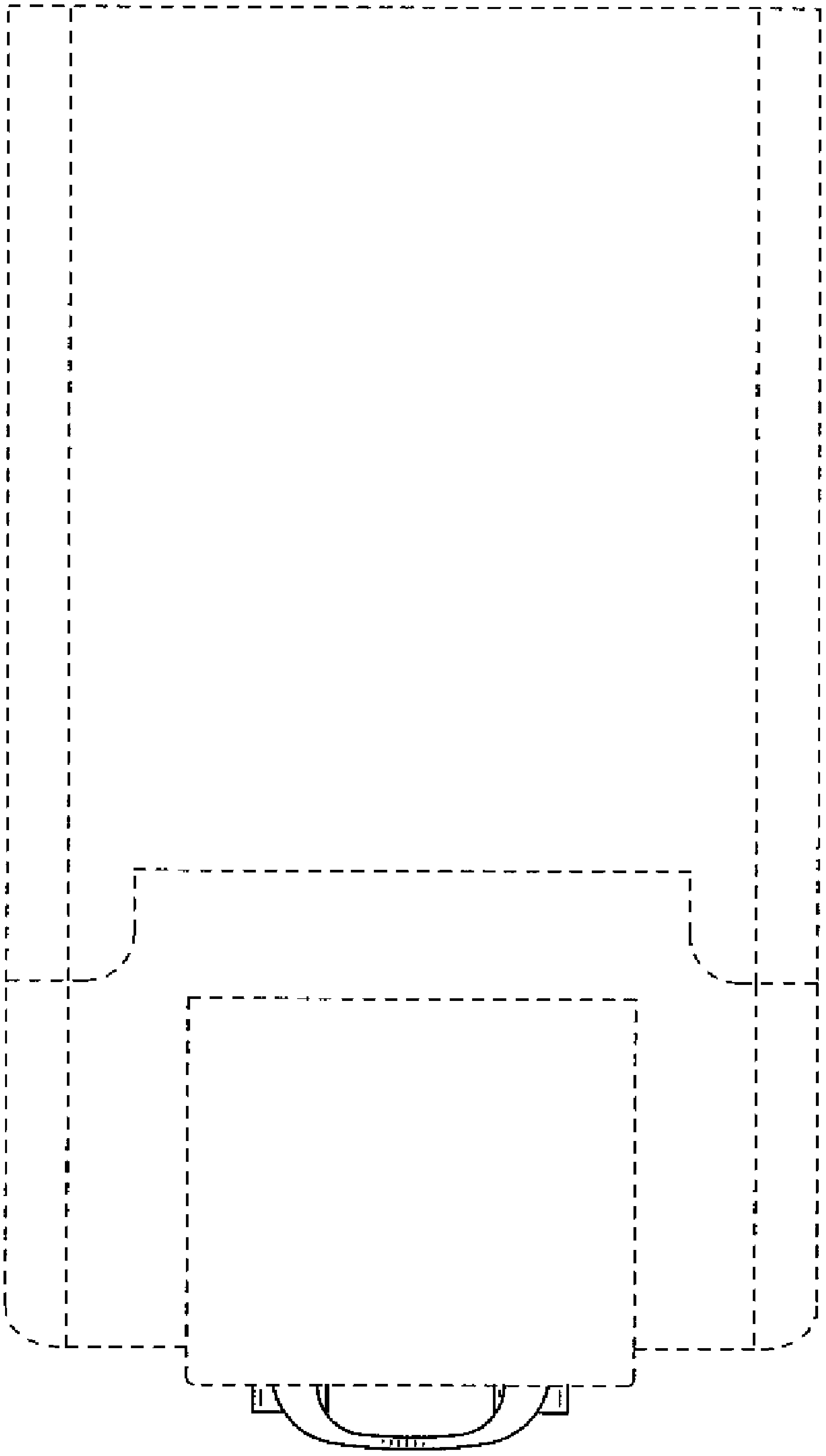


FIG. 6

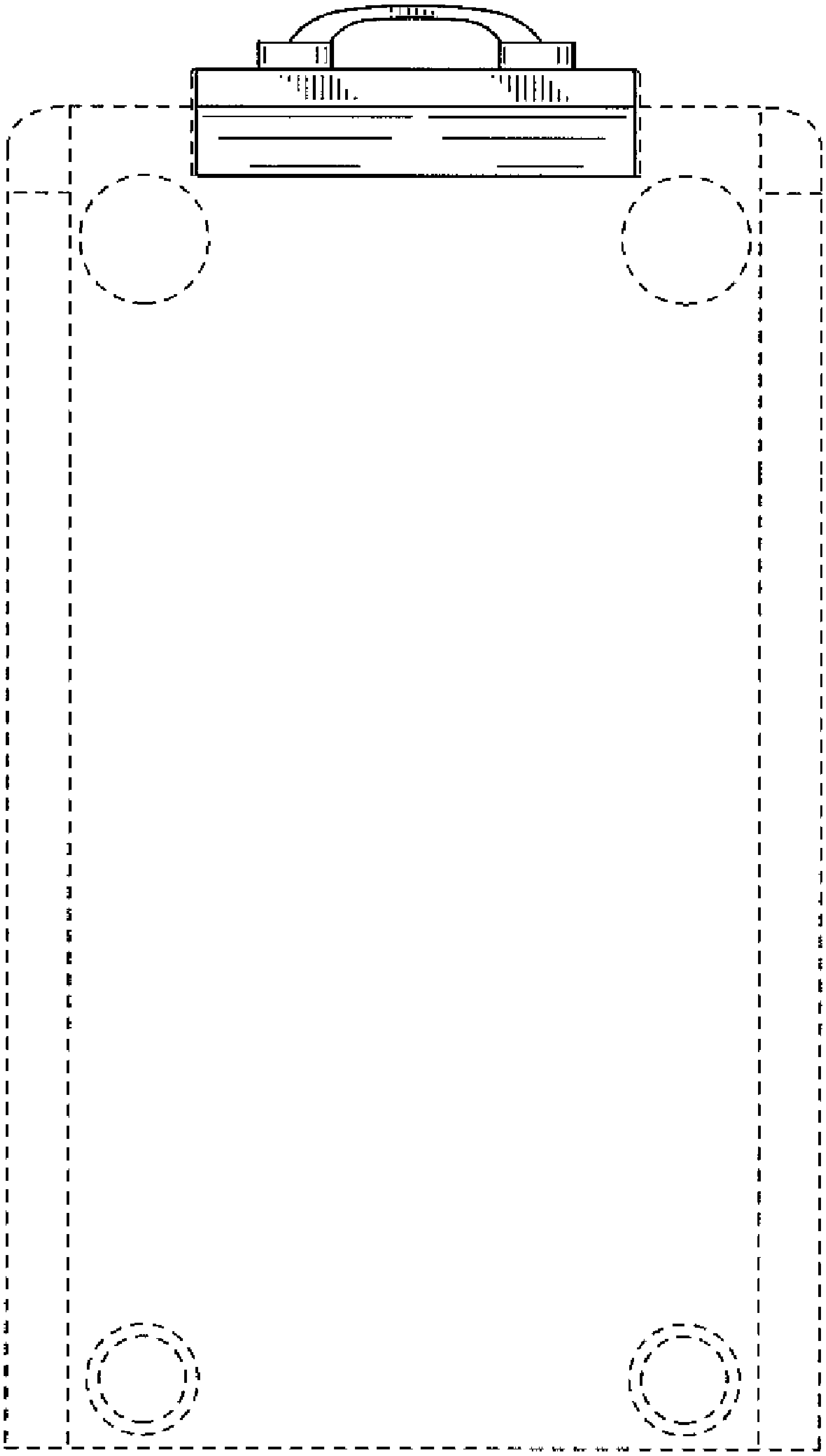


FIG. 7

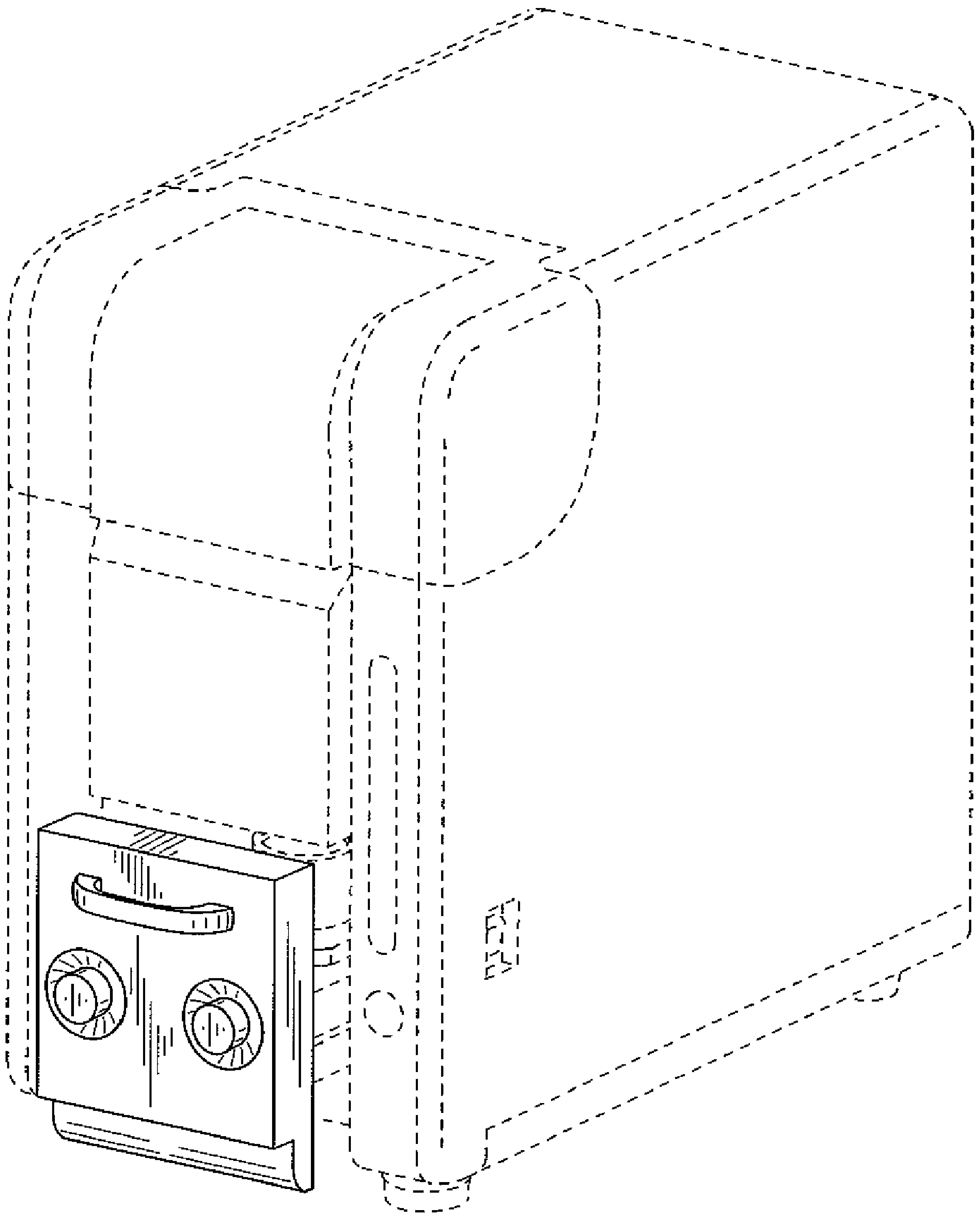


FIG. 8